

#7 Supple IPS
DTMUGhT
XA-9387 11-20-0



PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

Hitoshi TAKEUCHI

Appln. No.: 09/714,183

Group Art Unit: 2877

Filed: November 17, 2000

For: ABERRATION MEASURING APPARATUS, ABERRATION MEASURING METHOD, PROJECTION EXPOSURE APPARATUS HAVING THE SAME MEASURING APPARATUS, DEVICE MANUFACTURING METHOD USING THE SAME MEASURING METHOD, AND EXPOSURE METHOD

RECEIVED
NOV 15 2002
MAIL ROOM
TC 2808

* * *

THIRD SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT
AND STATEMENT UNDER 37 C.F.R. § 1.97(e)

Commissioner for Patents
Washington, D.C. 20231

Sir:

Supplementing the Information Disclosure Statement dated May 29, 2002, and without any assertion as to materiality or prior art effect, the documents listed on the attached Form PTO-1449 are hereby cited.

The documents on the attached List were recently cited in a European Search Report.

The Commissioner is hereby authorized to charge to Deposit Account No. 50-1165 any fees under 37 C.F.R. §§ 1.16 and 1.17 that may be required by this paper, and to credit any overpayment to that Account.

STATEMENT UNDER 37 C.F.R. § 1.97(e)

The undersigned hereby states that each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Statement.

Respectfully submitted,

MWS:sjk

Miles & Stockbridge P.C.
1751 Pinnacle Drive
Suite 500
McLean, Virginia 22102-3833
(703) 903-9000

By: 

Mitchell W. Shapiro
Reg. No. 31,568

November 14, 2002



FORM PTO-1449

Atty. Docket No.

Appln. No.

LIST OF DOCUMENTS CITED BY APPLICANT

XA-9387

09/714,183

Applicant

Hitoshi TAKEUCHI et al.

Filing Date

November 17, 2000

Group

2877

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date
	AA	5,202,748	04/13/93	MacDonald et al.	356	360	
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Country	Class	Sub-class	Translation
	AL						
	AM						
	AN						
	AO						
	AP						
	AQ						

OTHER (including author, title, date, pertinent pages, etc.)

AR Gourlay et al., "A real-time closed-loop liquid crystal adaptive optics system: first results", Optics Communications, Vol. 137, No. 1-3, April 15, 1997, pp. 17-21.

AS

AT

Examiner

Date Considered

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.